

N-channel 600 V, 0.395 Ω typ., 9 A MDmesh™ M2 Power MOSFET in an IPAK package

Datasheet - production data

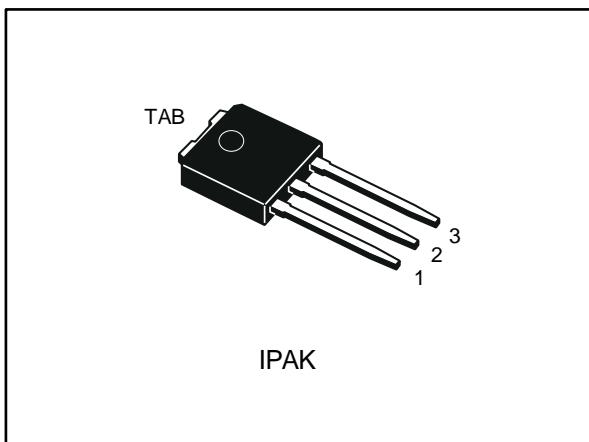
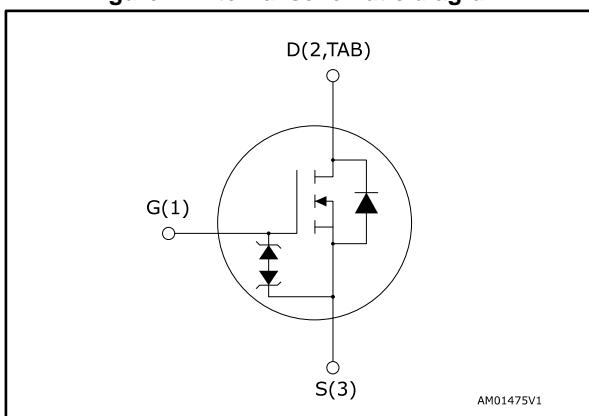


Figure 1: Internal schematic diagram



Features

Order code	V _{DS}	R _{DS(on)} max.	I _D	P _{TOT}
STU12N60M2	600 V	0.450 Ω	9 A	85 W

- Extremely low gate charge
- Excellent output capacitance (C_{oss}) profile
- 100% avalanche tested
- Zener-protected

Applications

- Switching applications

Description

This device is an N-channel Power MOSFET developed using MDmesh™ M2 technology. Thanks to its strip layout and an improved vertical structure, the device exhibits low on-resistance and optimized switching characteristics, rendering it suitable for the most demanding high efficiency converters.

Table 1: Device summary

Order code	Marking	Package	Packing
STU12N60M2	12N60M2	IPAK	Tube

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1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{GS}	Gate-source voltage	± 25	V
I_D	Drain current (continuous) at $T_{case} = 25^\circ C$	9	A
	Drain current (continuous) at $T_{case} = 100^\circ C$	5.7	
$I_{DM}^{(1)}$	Drain current (pulsed)	36	A
P_{TOT}	Total dissipation at $T_{case} = 25^\circ C$	85	W
$dv/dt^{(2)}$	Peak diode recovery voltage slope	15	V/ns
$dv/dt^{(3)}$	MOSFET dv/dt ruggedness	50	
T_{stg}	Storage temperature	-55 to 150	$^\circ C$
T_j	Operating junction temperature		

Notes:

(1) Pulse width is limited by safe operating area.

(2) $I_{SD} \leq 9$ A, $dI/dt=400$ A/ μ s; $V_{DS(\text{peak})} < V_{(BR)DSS}$, $V_{DD} = 80\%$ $V_{(BR)DSS}$.(3) $V_{DS} \leq 480$ V.**Table 3: Thermal data**

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case	1.47	$^\circ C/W$
$R_{thj-amb}$	Thermal resistance junction-ambient	62.5	

Table 4: Avalanche characteristics

Symbol	Parameter	Value	Unit
$I_{AR}^{(1)}$	Avalanche current, repetitive or not repetitive	2.6	A
$E_{AR}^{(2)}$	Single pulse avalanche energy	117	mJ

Notes:(1) Pulse width limited by T_{jmax} .(2) starting $T_j = 25^\circ C$, $I_D = I_{AR}$, $V_{DD} = 50$ V.

2 Electrical characteristics

($T_{\text{case}} = 25^\circ\text{C}$ unless otherwise specified)

Table 5: Static

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$V_{\text{GS}} = 0 \text{ V}, I_D = 1 \text{ mA}$	600			V
I_{DSS}	Zero gate voltage drain current	$V_{\text{GS}} = 0 \text{ V}, V_{\text{DS}} = 600 \text{ V}$			1	μA
		$V_{\text{GS}} = 0 \text{ V}, V_{\text{DS}} = 600 \text{ V}, T_{\text{case}} = 125^\circ\text{C}$			100	
I_{GSS}	Gate-body leakage current	$V_{\text{DS}} = 0 \text{ V}, V_{\text{GS}} = \pm 25 \text{ V}$			± 10	μA
$V_{\text{GS}(\text{th})}$	Gate threshold voltage	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250 \mu\text{A}$	2	3	4	V
$R_{\text{DS}(\text{on})}$	Static drain-source on-resistance	$V_{\text{GS}} = 10 \text{ V}, I_D = 4.5 \text{ A}$		0.395	0.450	Ω

Table 6: Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	$V_{\text{DS}} = 100 \text{ V}, f = 1 \text{ MHz}, V_{\text{GS}} = 0 \text{ V}$	-	538	-	pF
C_{oss}	Output capacitance		-	29	-	
C_{rss}	Reverse transfer capacitance		-	1.1	-	
$C_{\text{oss eq.}}^{(1)}$	Equivalent output capacitance	$V_{\text{DS}} = 0 \text{ to } 480 \text{ V}, V_{\text{GS}} = 0 \text{ V}$	-	106	-	pF
R_G	Intrinsic gate resistance	$f = 1 \text{ MHz}, I_D = 0 \text{ A}$	-	7	-	Ω
Q_g	Total gate charge	$V_{\text{DD}} = 400 \text{ V}, I_D = 9 \text{ A}, V_{\text{GS}} = 10 \text{ V}$ (see Figure 15: "Gate charge test circuit")	-	16	-	nC
Q_{gs}	Gate-source charge		-	2.3	-	
Q_{gd}	Gate-drain charge		-	8.5	-	

Notes:

⁽¹⁾ $C_{\text{oss eq.}}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS} .

Table 7: Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{\text{d}(\text{on})}$	Turn-on delay time	$V_{\text{DD}} = 300 \text{ V}, I_D = 4.5 \text{ A}$ $R_G = 4.7 \Omega, V_{\text{GS}} = 10 \text{ V}$ (see Figure 14: "Switching times test circuit for resistive load" and Figure 19: "Switching time waveform")	-	9.2	-	ns
t_r	Rise time		-	9.2	-	
$t_{\text{d}(\text{off})}$	Turn-off delay time		-	5	-	
t_f	Fall time		-	18	-	

Table 8: Source-drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		9	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		36	A
$V_{SD}^{(2)}$	Forward on voltage	$V_{GS} = 0 \text{ V}, I_{SD} = 9 \text{ A}$	-		1.6	V
t_{rr}	Reverse recovery time	$I_{SD} = 9 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}, V_{DD} = 60 \text{ V}$ (see Figure 16: "Test circuit for inductive load switching and diode recovery times")	-	284		ns
Q_{rr}	Reverse recovery charge		-	2.4		μC
I_{RRM}	Reverse recovery current		-	17		A
t_{rr}	Reverse recovery time	$I_{SD} = 9 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}, V_{DD} = 60 \text{ V}, T_j = 150 \text{ }^\circ\text{C}$ (see Figure 16: "Test circuit for inductive load switching and diode recovery times")	-	404		ns
Q_{rr}	Reverse recovery charge		-	3.5		μC
I_{RRM}	Reverse recovery current		-	17.5		A

Notes:

(1) Pulse width is limited by safe operating area.

(2) Pulse test: pulse duration = 300 μs , duty cycle 1.5%.

2.1 Electrical characteristics (curves)

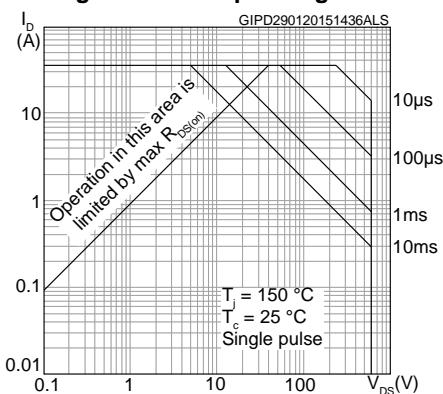
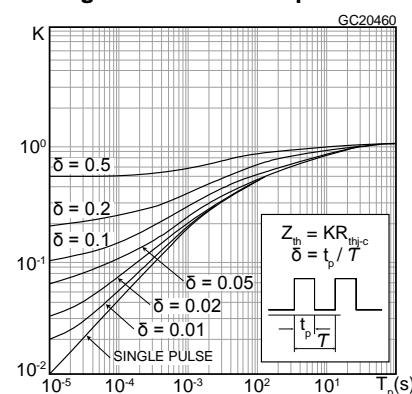
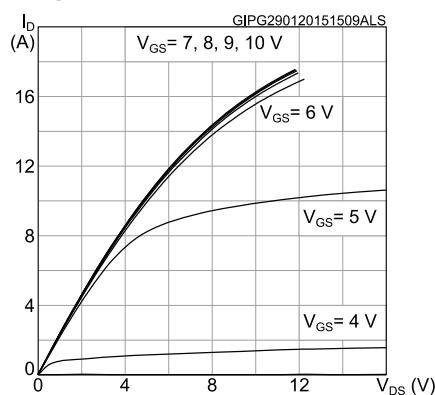
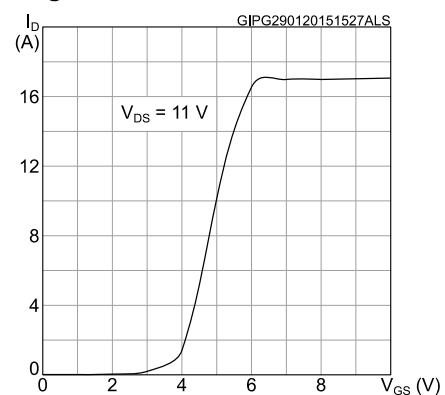
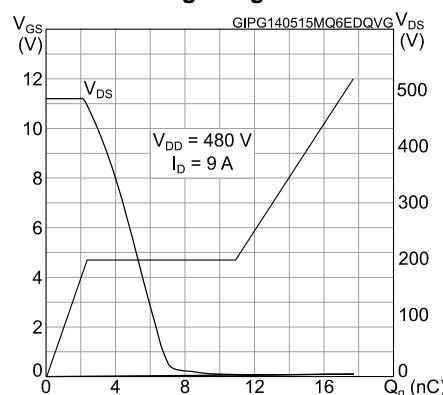
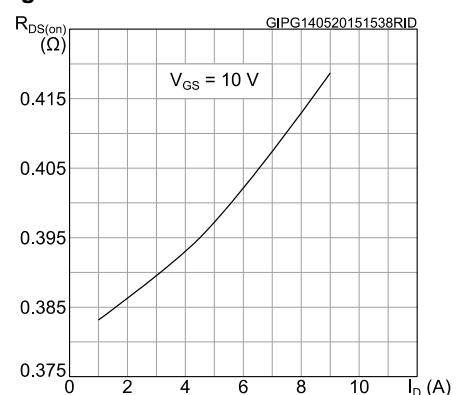
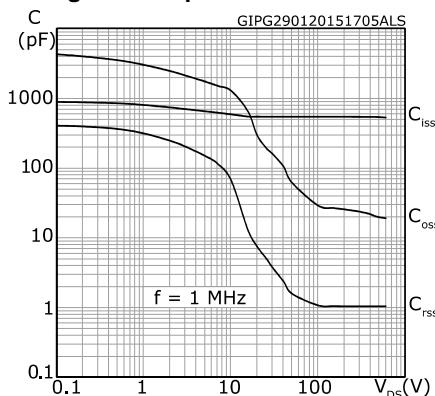
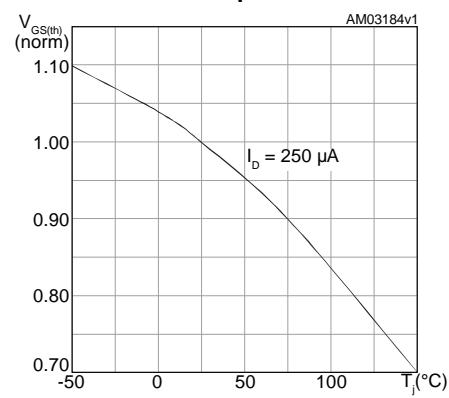
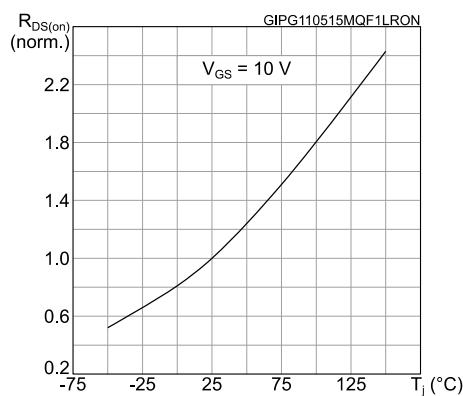
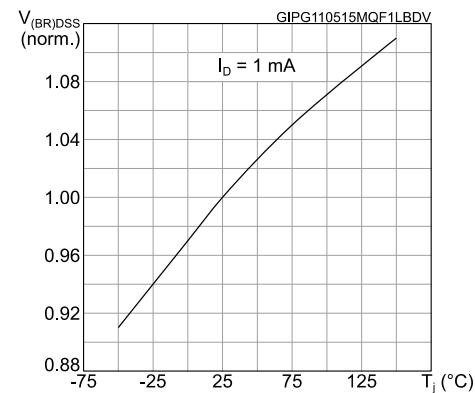
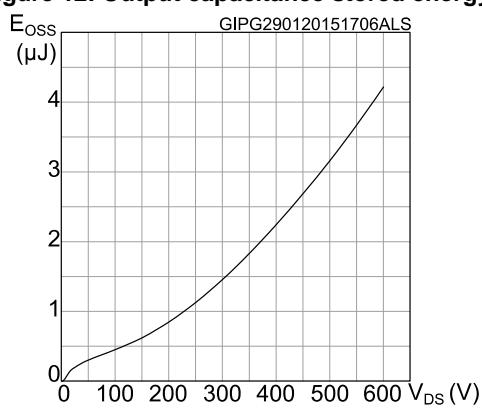
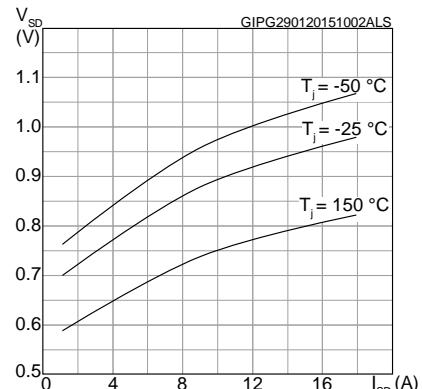
Figure 2: Safe operating area**Figure 3: Thermal impedance****Figure 4: Output characteristics****Figure 5: Transfer characteristics****Figure 6: Gate charge vs gate-source voltage****Figure 7: Static drain-source on-resistance**

Figure 8: Capacitance variations**Figure 9: Normalized gate threshold voltage vs temperature****Figure 10: Normalized on-resistance vs temperature****Figure 11: Normalized V(BR)DSS vs temperature****Figure 12: Output capacitance stored energy****Figure 13: Source- drain diode forward characteristics**

3 Test circuits

Figure 14: Switching times test circuit for resistive load

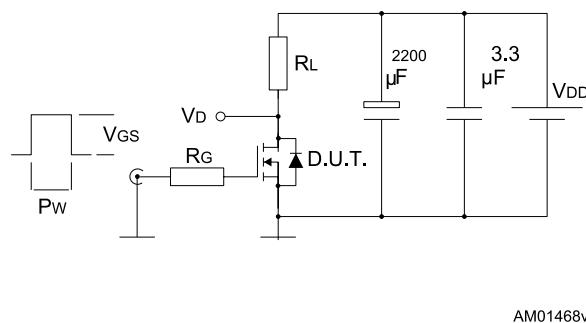


Figure 15: Gate charge test circuit

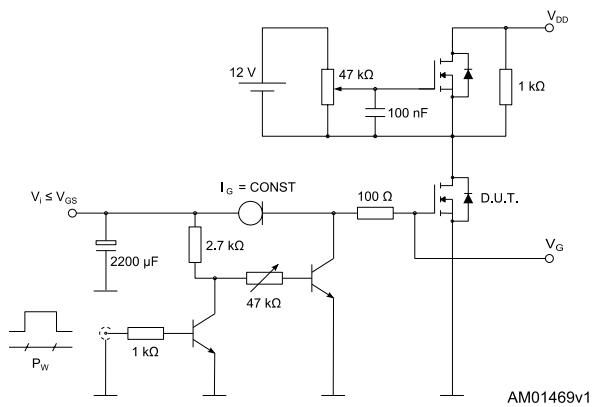


Figure 16: Test circuit for inductive load switching and diode recovery times

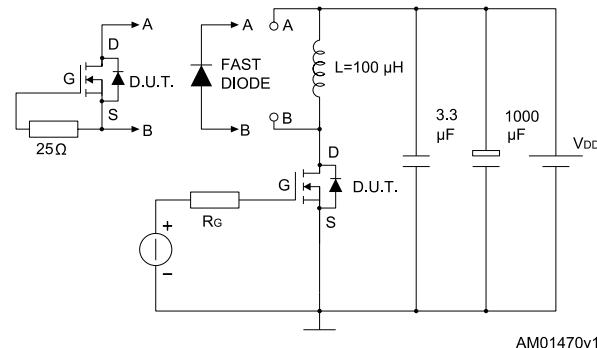


Figure 17: Unclamped inductive load test circuit

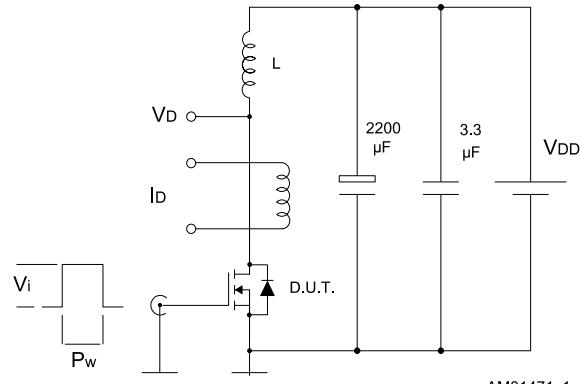


Figure 18: Unclamped inductive waveform

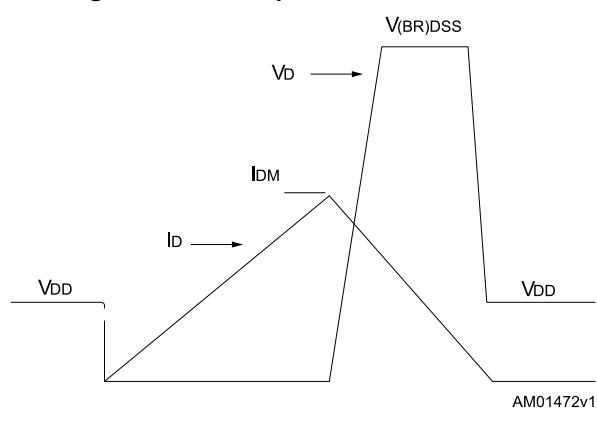
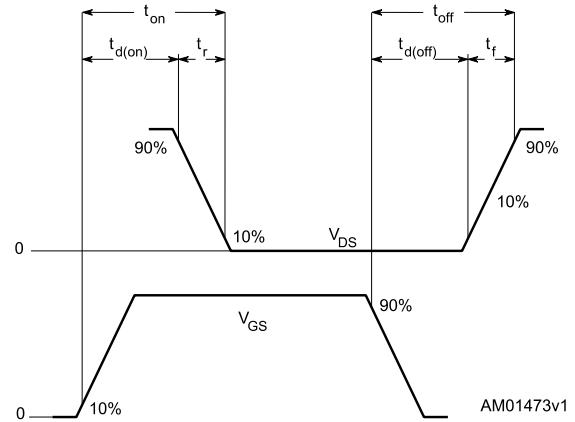


Figure 19: Switching time waveform



4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com.
ECOPACK® is an ST trademark.

4.1 IPAK (TO-251) Type A package information

Figure 20: IPAK (TO-251) type A package outline

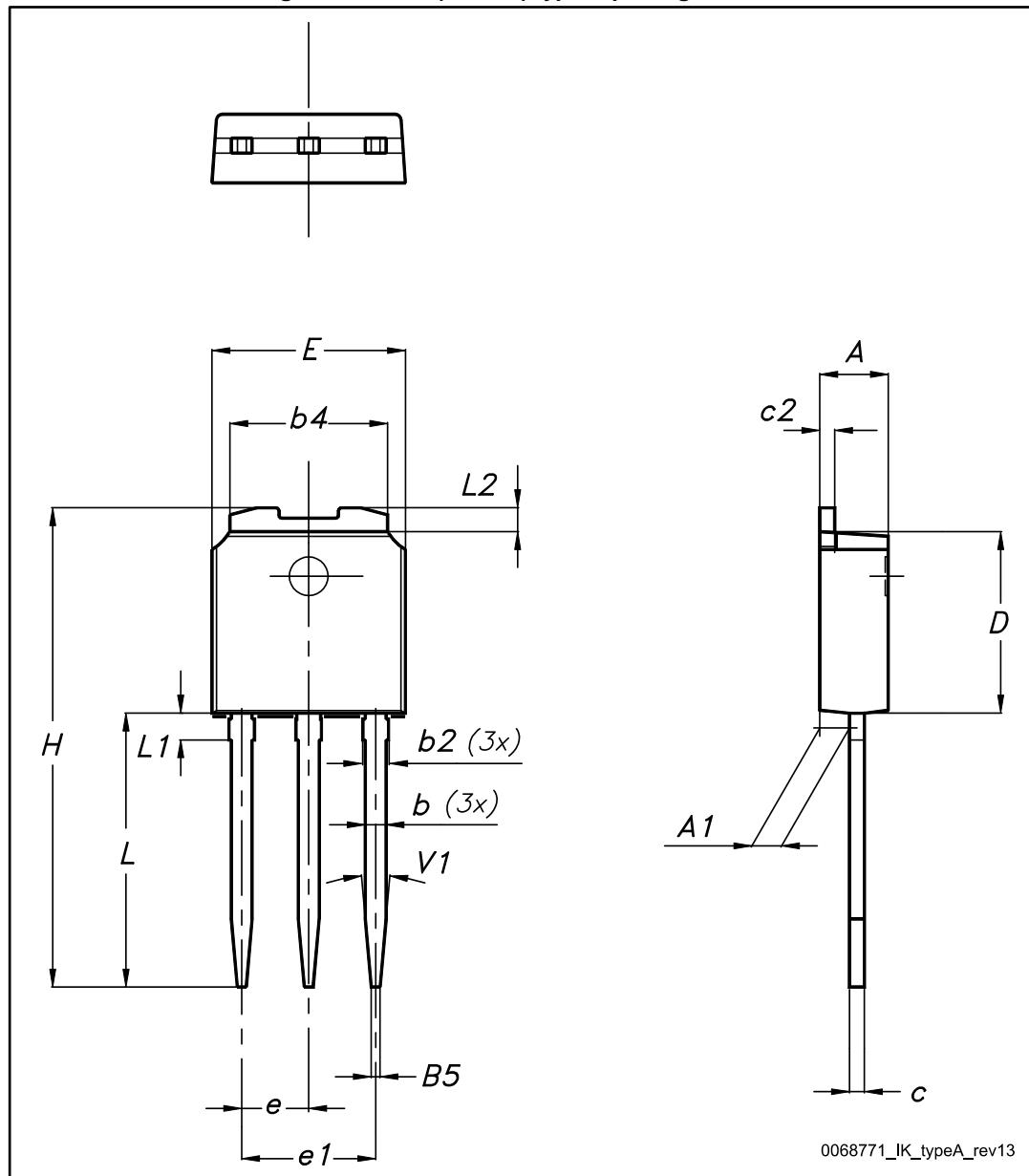


Table 9: IPAK (TO-251) type A package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	2.20		2.40
A1	0.90		1.10
b	0.64		0.90
b2			0.95
b4	5.20		5.40
B5		0.30	
c	0.45		0.60
c2	0.48		0.60
D	6.00		6.20
E	6.40		6.60
e		2.28	
e1	4.40		4.60
H		16.10	
L	9.00		9.40
L1	0.80		1.20
L2		0.80	1.00
V1		10°	

5 Revision history

Table 10: Document revision history

Date	Revision	Changes
22-May-2015	1	First release.

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